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Instructor: Professor Vishwani D. Agrawal, vagrawal@eng.auburn.edu, Broun 323, 334-844-1853. Text book: Essentials of Electronic Testing for Digital, Memory and Mixed-Signal VLSI Circuits by Bushnell and Agrawal, Springer, 2000. HOMEWORK (30%): Homework 1 -- Problems 1.2 and 1.4, assigned 1/12/06, due 1/26/06, solution

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